

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10573646	MIZUSHIMA ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	DEREK S CHAPEL	2872

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
359	483, 491, 900 (text only, see attached)	12/6/2008	DSC
264	1.1, 1.31, 1.34 (text only, see attached)	12/6/2008	DSC

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Consulted with Arnel Lavarias about the search	12/5/2008	DSC

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

/D. S. C./  
Examiner.Art Unit 2872